

Notice of References Cited

Application/Control No.

09/855,177

Applicant(s)/Patent Under
Reexamination
WALDFRIED ET AL.

Examiner

Khanh Duong

Art Unit

2822

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,660,682	08-1997	Zhao et al.	438/715
	B	US-6,114,259	09-2000	Sukharev et al.	438/789
	C	US-5,352,636	10-1994	Beinglass, Israel	438/475
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP 1081751 A2	07-2001	EP	Cohen et al.	
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	X	

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